Search Notes



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10/643,746

Examiner

James D. Stein

Applicant(s)/Patent under Reexamination

SUMMERS ET AL.

Art Unit

2874

SEARCHED					
Class	Subclass	Date	Examiner		
385	37, 129,131	8/22/2005	JDS		
65	385	8/22/2005	JDS		
427	163.2	8/22/2005	JDS		
		,			
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
385	37,129 131	8/22/2005	JDS		
65	385	8/22/2005	JDS		
427	163.2	8/22/2005	JDS		
	-				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
See attached EAST search history	8/22/2005	JDS
USPGPUB interference search see attached EAST search history	8/22/2005	JDS
Partial Classification search: 385/14, 129-132 (photonic crystal/bandgap)	8/22/2005	JDS
PLUS keword search	8/23/2005	JDS
IEEE explore database search	8/22/2005	JDS